

PATENT  
Customer No. 22,852  
Attorney Docket No. 3180.0342

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: )  
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NOBUHIRO KOMINE )  
 )  
Application No.: 10/721,903 ) Group Art Unit: 2851  
 )  
Filed: November 26, 2003 ) Examiner: D. Rutledge  
 )  
For: RETICLE, EXPOSURE ) Confirmation No.: 9102  
MONITORING METHOD, )  
EXPOSURE METHOD AND )  
MANUFACTURING METHOD FOR )  
SEMICONDUCTOR DEVICE )

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicant brings to the attention of the Examiner the documents on the attached listing. This Information Disclosure Statement is being filed concurrently with a Request for Continued Examination Transmittal in the above-referenced application.

Copies of the listed foreign and non-patent literature documents are attached.

Applicant respectfully requests that the Examiner consider the listed documents and indicate that they were considered by making appropriate notations on the attached form.

In lieu of a statement of relevance or translation of the non-English documents, enclosed is a Notice of Grounds for Rejection issued by the Japanese Patent Office in a counterpart Japanese application, mailed June 21, 2005, citing these documents and setting forth the relevance thereof. In addition, an English-language translation of the Notice is attached. Further, Applicant notes that Japanese Patent Laid-Open No. 2000-310850 is discussed on pages 2-3 of the present specification.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claim in the application and applicant determines that the cited documents do not constitute "prior art" under United States law, applicant reserves the right to present to the office the relevant facts and law regarding the appropriate status of such documents.

Applicant further reserves the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.


Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,  
GARRETT & DUNNER, L.L.P.

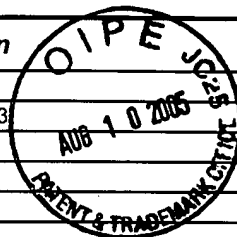
Dated: \_\_\_\_\_

8/10/05

By: \_\_\_\_\_

  
Richard V. Burgujian  
Reg. No. 31,744

IDS Form PTO/SB/08: Substitute for form 1449A/PTO				<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				Application Number	10/721,903
				Filing Date	November 26, 2003
				First Named Inventor	Nobuhiro Komine
				Art Unit	2851
				Examiner Name	D. Rutledge
Attorney Docket Number	3180.0342				
Sheet	1	of	1		



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-			
		US-			
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**Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.**

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
		JP 2001-319871	11/16/01	Nikon Corp.		Abstract
		JP 2000-310850	11/7/00	Toshiba Corp.		Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>
		Notice of Grounds for Rejection, issued by the Japanese Patent Office, mailed June 21, 2005, in Japanese Patent Application Serial No. P2002-342798, and English-language translation thereof	
		DIRKSEN et al., "Focus and exposure dose determination using stepper alignment," SPIE (1996), 2726:799-808	
		STARIKOV, "Exposure Monitor Structure," SPIE (1990), 1261:315-324	

Examiner Signature	Date Considered
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.